

<b>Notice of References Cited</b>	Application/Control No. 10/598,025		Applicant(s)/Patent Under Reexamination DE HAAN ET AL.	
	Examiner Kenneth Chang		Art Unit 4171	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0009604 A1	07-2001	Ando et al.	386/95
*	B	US-2001/0028725 A1	10-2001	Nakagawa et al.	382/100
*	C	US-2001/0030959 A1	10-2001	Ozawa et al.	370/386
*	D	US-2001/0042252 A1	11-2001	Yamaguchi et al.	725/61
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
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#### FOREIGN PATENT DOCUMENTS

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	N					
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#### NON-PATENT DOCUMENTS

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